- O Distribution initiale de phase et enfouissement des domaines d'antiphase lors de la croissance III-Vs/Si (001)

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Part of this work was sponsored by French program on "Investments for the future" (Equipex EXTRA, ANR11-EQPX-0016), the ANR- DFG FILTER project (ANR-20-CE92-0045) and the ANR PIANIST (ANR-21-CE09-0020) and NUAGES (ANR-21-CE24-0006) projects.



Chrs

A

Photonic integrated circuits (PICs):



PIC from Haisheng Rong's (Intel) presentation on the prospects of silicon photonics at SPIE Advanced Lithography and Patterning

Context

Si

Ga

Chrs

3

Heterogeneous integration



Monolithic integration

As Sb Molecular beam epitaxy

C. Besancon: «Intégration hybride de sources laser III-V sur Si par collage direct et recroissance pour les télécommunications à haut débit», 2020 • H. Yoon et al, Sci. Adv.8, 2022, DOI:10.1126/sciadv.add5328







Challenges



Few demonstrations of APB annihilation

No clear explanation of the mechanism



Les M. Chrs

5

M. Coste: «Intégration hétérogène de GaAs sur Si à partir de nano-germes : étude de la nucléation et de la croissance de micro-cristaux sur substrats Si (001) et (111)», 2018



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A. Ponchet et al, Applied Physics letters, 2018https://doi.org/10.1063/1.5055056



One domain is buried because it grows slower

C. Cornet *et al., Phys. Rev. Materials*, vol. 4, nº 5, p. 053401, mai 2020, doi: 10.1103/PhysRevMaterials.4.053401 Kinetic Monte Carlo simulation by Vladimir Kaganer (PDI)

Chrs

A

8



A

9



ies in cars 10



1**e/s (M.) Chrs** 11



ies in cars 12







ies in cars 13

M. Rio Calvo et al, Advanced Electronic Materials 8, 2100777 (2022)





ies in cars 14



MPD



Depth difference **7**: 3% growth rate difference

APD



500 nm

Si 0.5°

CIPITS 16



One domain grows slower and is buried

Universal burying





Domain width = mono-atomic terrace width



GaAs APBs burying **LOW** T°C growth 7.3 nm nm GaAs Si 0.50 0 nm 500 nm APD stripes shrinks ies in cars 19





GaAs APBs burying

100 nm LOW T°C + **400 nm MT°C**



GaAs APBs burying

Islands grow faster in [110] direction because of a difference in diffusion length

[110]

50 nm GaAs

23



One phase expands faster towards the other

Universal burying



Summary

Lower symmetry of III-V: two phases







Miscut transfer in [110] direction breaks the symmetry





Anisotropy faster incorporation in V-steps faster island elongation in [110]



15 nm

500 nm GaSb on Si 0.5°



500 nm GaAs on Si 0.5°



500 nm GaSb on Ge 0.5°



500 nm InAs on Ge 0.5°



Thank you for your attention

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See M. Fagot's poster «ICLs à 3,3 µm sur substrats de GaSb, GaAs et Si (001)»

A. Gilbert et al, Advanced Optical Materials, May 2023, https://doi.org/10.1002/adom.202203050











Regime transition

Stable island size > Si terraces

520°C

470°C

420°C

370°C

350°C

Nucleation-driven

Stable island size < Si terraces

Terrace-driven



What could go wrong?

Y. B. Bolkhovityanov and O. P. Pchelyakov, Phys.-Uspekhi 51, 437 (2008)



y (µm)

